2SD1266, 2SD1266A

Silicon NPN triple diffusion planar type

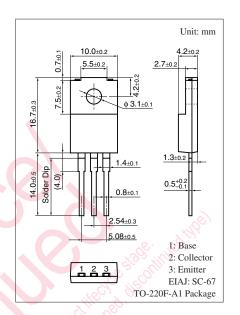
For power amplification

■ Features

- \bullet High forward current transfer ratio $h_{F\!E}$ which has satisfactory linearity
- ullet Low collector-emitter saturation voltage $V_{CE(sat)}$
- Full-pack package which can be installed to the heat sink with one screw

■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage	2SD1266	V_{CBO}	60	V
(Emitter open)	2SD1266A		80	
Collector-emitter voltage	2SD1266	V _{CEO}	60	V
(Base open)	2SD1266A		80	
Emitter-base voltage (Col	V_{EBO}	6	V	
Collector current	I_C	3	A	
Peak collector current	I_{CP}	5	A	
Collector power	$T_C = 25^{\circ}C$	P _C	35	W
dissipation		A. (2.0	
Junction temperature	T _j	150	°C	
Storage temperature		T _{stg}	-55 to +150	°C



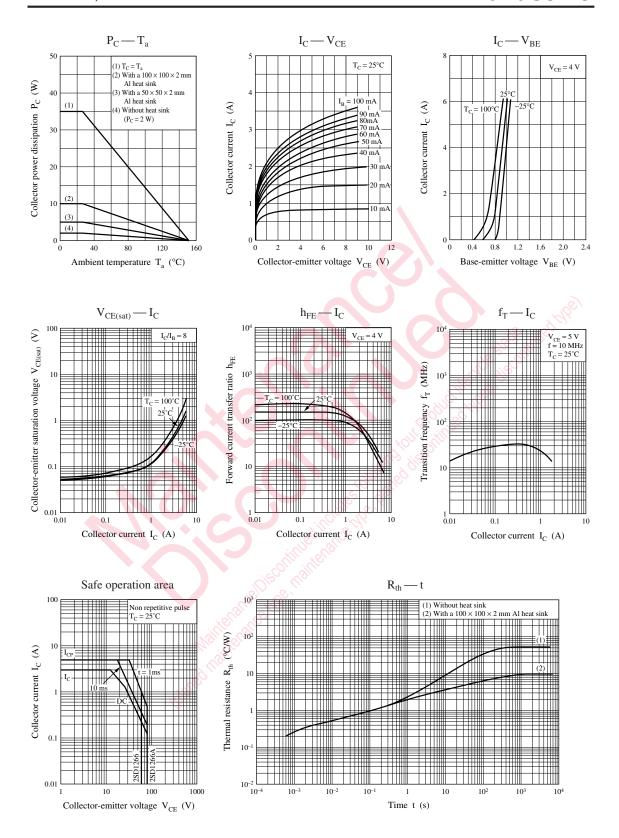
■ Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage	2SD1266	V _{CEO}	$I_{\rm C} = 30 \text{ mA}, I_{\rm B} = 0$	60			V
(Base open)	2SD1266A		dill ce is.	80			
Base-emitter voltage		V _{BE}	$V_{CE} = 4 \text{ V}, I_{C} = 3 \text{ A}$			1.8	V
Collector-emitter cutoff	2SD1266	I_{CES}	$V_{CE} = 60 \text{ V}, V_{BE} = 0$			200	μΑ
current (E-B short)	2SD1266A		$V_{CE} = 80 \text{ V}, V_{BE} = 0$			200	
Collector-emitter cutoff	2SD1266	I_{CEO}	$V_{CE} = 30 \text{ V}, I_{B} = 0$			300	μΑ
current (Base open)	2SD1266A	Cite of	$V_{CE} = 60 \text{ V}, I_{B} = 0$			300	
Emitter-base cutoff current (Collector open)		I_{EBO}	$V_{EB} = 6 \text{ V}, I_C = 0$			1	mA
Forward current transfer ratio		h _{FE1} *	$V_{CE} = 4 \text{ V}, I_{C} = 1 \text{ A}$	70		320	_
		h _{FE2}	$V_{CE} = 4 \text{ V}, I_{C} = 3 \text{ A}$	10			
Collector-emitter saturation voltage		V _{CE(sat)}	$I_C = 3 \text{ A}, I_B = 0.375 \text{ A}$			1.2	V
Transition frequency		f_T	$V_{CE} = 10 \text{ V}, I_{C} = 0.5 \text{ A}, f = 10 \text{ MHz}$		30		MHz
Turn-on time		t _{on}	$I_C = 1 A, I_{B1} = 0.1 A, I_{B2} = -0.1 mA$		0.5		μs
Storage time		t _{stg}	$V_{CC} = 50 \text{ V}$		2.5		μs
Fall time		$t_{\rm f}$			0.4		μs

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. *: Rank classification

Rank	Q	Р	0	
h _{FE1}	70 to 150	120 to 250	160 to 320	



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